

Abstract of the Disclosure:

A data memory to be tested is connected to a processing unit.

Data items to be stored are produced from a test pattern data item in the processing unit and are stored in the data memory.

5 The data memory is tested in that the test pattern data items are received from a test device, processed using a first function to form data items to be stored, and the data items are then stored. After the stored data items are read from the memory they are processed with a second function to form test data items whose number is once more smaller than the stored data items that are read from the memory.

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